



GaN HEMT 28V, 4W, C band RF Power Transistor

Description

The XTAH78004C6 is a 4W GaN HEMT, designed for multiple applications, within 4-8GHz.

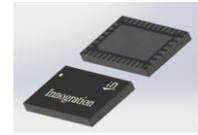
The transistor is available in a highly cost effective 10*6mm, surface mount, QFN package with 100% production test to ensure the quality and consistency.

It can be used in CW, Pulse and any other modulation modes.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.

- Typical 6-8GHz broadband performance with device soldered

XTAH78004C6



$V_{DS}=28V$, $I_{DQ}=6mA$, $V_{GS}=-2.62V$

FREQ (MHZ)	P1dB (dBm)	P1dB (W)	P1dB Eff (%)	P1dB Gain (dB)	P3dB (dBm)	P3dB (W)	P3dB Eff (%)
6000	35	3.2	34.0	12.01	37.23	5.3	40.7
6500	35.27	3.4	36.0	14.02	37.39	5.5	43.3
7000	35.57	3.6	40.7	12.92	37.26	5.3	46.4
7500	34.89	3.1	35.6	11.08	36.53	4.5	40.2
8000	35.05	3.2	38.1	12.37	36.54	4.5	42.1

Applications

- C band power amplifier

Important Note: Proper Biasing Sequence for GaN HEMT Transistors

Turning the device ON

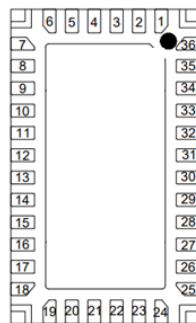
1. Set VGS to the pinch--off (VP) voltage, typically $-5V$
2. Turn on VDS to nominal supply voltage
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically $-5V$
3. Reduce VDS down to 0 V
4. Turn off VGS

Figure 1: Pin Connection definition

Transparent top view (Backside grounding for source)



Pin No.	Symbol	Description
8,9,10,11,	RF IN/Vgs	RF Input, Vgs bias
32,33,34,35	RF OUT/VDD	RFOutput, Drain bias
2,5,7,12,13,18,20,23,25,30,31,36, Package Base	GND	DC/RF Ground.
Rest Pins	NC	Not connected



Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain--Source Voltage	V_{DS}	+150	Vdc
Gate--Source Voltage	V_{GS}	-8 to +0.5	Vdc
Operating Voltage	V_{DD}	36	Vdc
Maximum gate current	I_{gs}	1	mA
Storage Temperature Range	T_{stg}	-65 to +150	°C
Case Operating Temperature	T_C	+150	°C
Operating Junction Temperature	T_J	+225	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case by FEA $T_C = 25^\circ\text{C}$, at $P_{diss} = 5\text{W}$	$R_{\theta JC}$	16	°C /W

Table 3. Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

DC Characteristics (main path, measured on wafer prior to packaging)

Characteristic	Conditions	Symbol	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{GS} = -8\text{V}$; $I_{DS} = 1\text{mA}$	V_{DSS}		150		V
Gate Threshold Voltage	$V_{DS} = 10\text{V}$, $I_D = 1\text{mA}$	$V_{GS(th)}$	-4		-2	V
Gate Quiescent Voltage	$V_{DS} = 28\text{V}$, $I_{DS} = 20\text{mA}$, Measured in Functional Test	$V_{GS(Q)}$		-2.57		V

Typical performance

Figure 2: Network analyzer output S11/S21

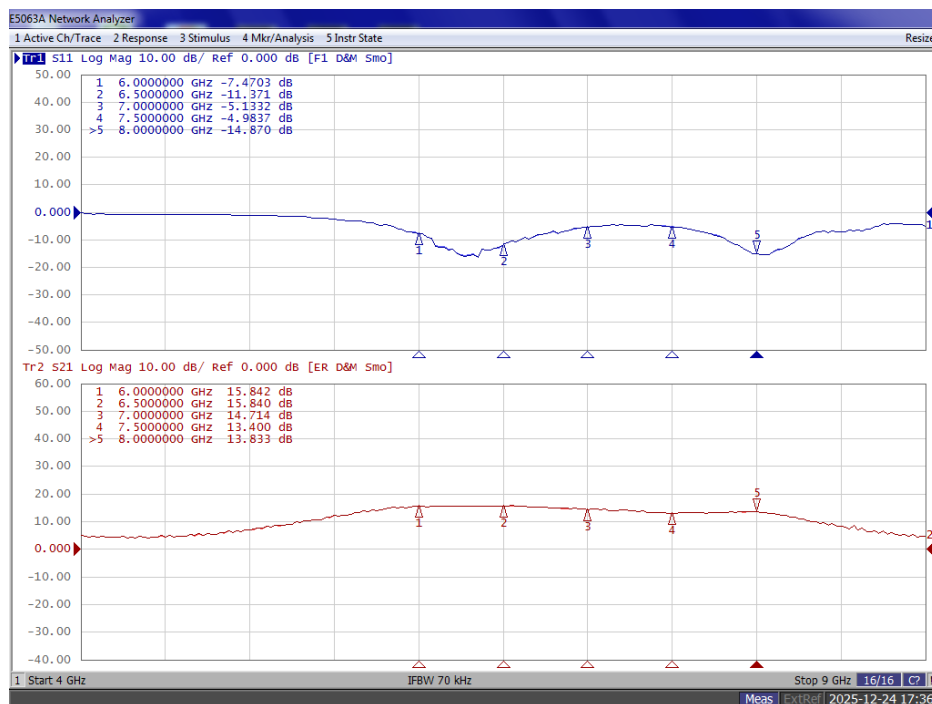


Figure 3: Picture of application board

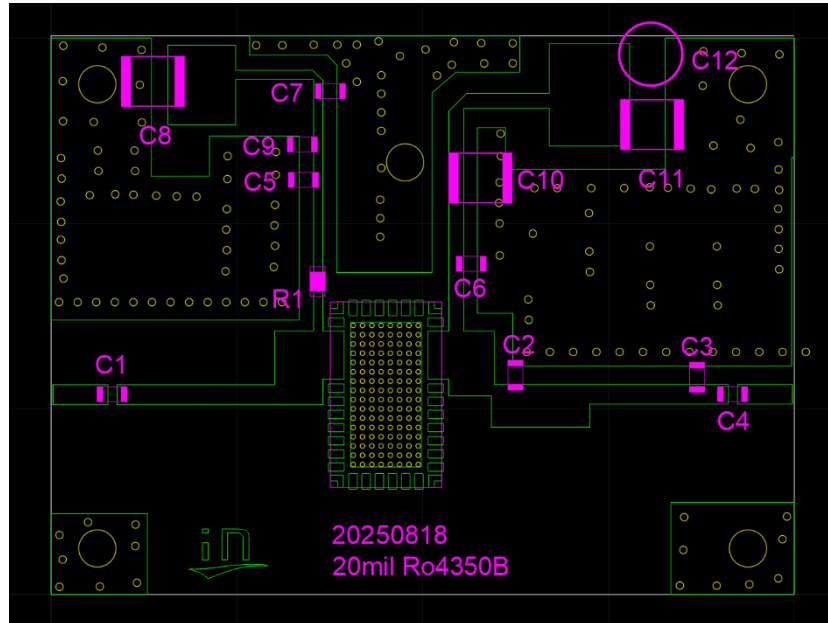
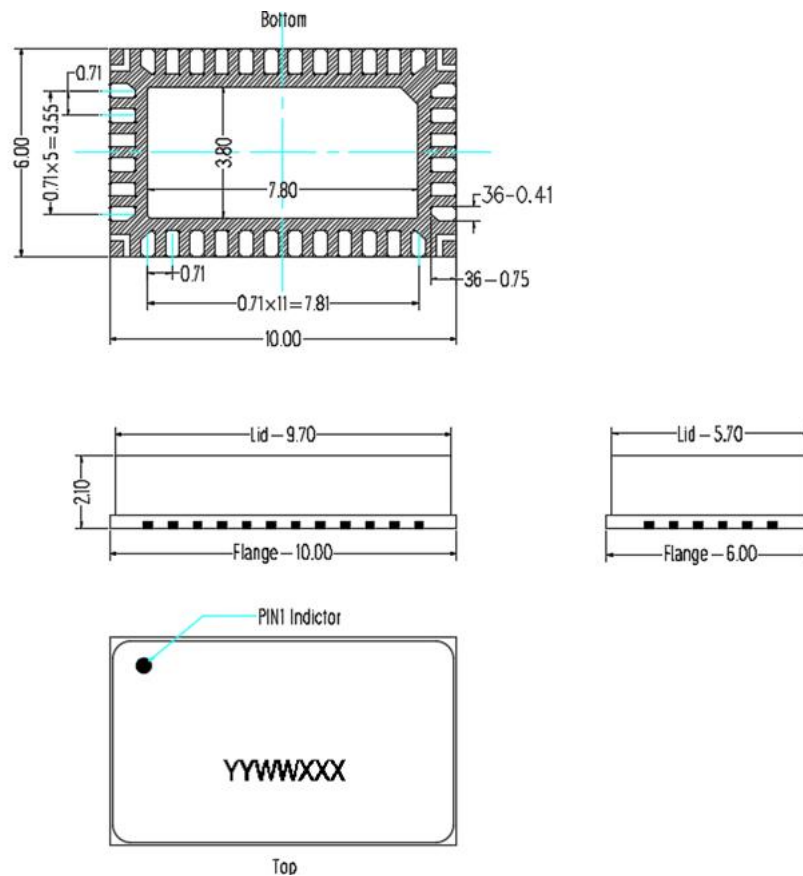


Table 4. Bill of materials of application board (PCB layout upon request, RO4350B 20mils)

Component	Value	Quantity
U1	XTAH78004C6	1
C1、C4、C5、C6	3.3pF	4
C2	0.2pF	1
C3	0.1pF	1
C7	10pF	1
C9	10nF	1
C8、C10、C11	10uF/63V	3
C12	470uF/63V	1
R1	10 Ω	1



10*6 Plastic Package



Notes:

1. All dimensions are in mm;
2. The tolerances unless specified are ± 0.2 mm.

Revision history

Table 4. Document revision history

Date	Revision	Datasheet Status
2025/12/24	V1.0	Preliminary Datasheet Creation

Application data based on: ZYX-25-49

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